


<b>Search Notes</b> 	<b>Application/Control No.</b> 10776736	<b>Applicant(s)/Patent Under Reexamination</b> DEWAELE, PIET
	<b>Examiner</b> Fujita, Katrina	<b>Art Unit</b> 2609

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
(382/289,128,131,132) text search only - see search history printouts	02/02/2007	KF
(378/4,20,37) text search only - see search history printouts	02/02/2007	KF
(702/150) text search only - see search history printouts	02/06/2007	KF
IEEE keyword and author search - see search history printouts	02/07/2007	KF
SPIE keyword and author search - see search history printouts	02/02/2007	KF
Updated (382/128,131,132) text search only - see search history printouts	01/16/2008	KF
Updated EAST text search - see search history printouts	05/13/2008	KF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner